## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | MEIER, MARKUS | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0014029 A1	08-2001	Suzuki et al.	363/141
*	В	US-5,886,408	03-1999	Ohki et al.	257/720
	С	US-			
	D	US-			
	E	US-			
Γ.	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-		. *	
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	Р					
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	R					
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## NON-PATENT DOCUMENTS

	NON-I ATENT DOCUMENTO							
*	l	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	υ							
	V							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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